



**Quad, SPST, CMOS, TTL-Compatible
Analog Switches**

DG308A/DG309/883B

1.0 SCOPE

1.1 This specification covers the detail requirements for two quad, SPST, CMOS switches. These circuits are processed in accordance with MIL-STD-883 and are fully compliant to paragraph 1.2.1.

It is highly recommended that this data sheet be used as a baseline for new military or aerospace source control drawings.

For typical applications and operating characteristics, consult Maxim's data books.

1.2 Part Numbers

Device	Part Number
-1	DG308AA(X)/883B
-2	DG309A(X)/883B

1.3 Package

(X)	Package	Description
K	K-16	16-Pin Ceramic Dual-In-Line Package (CERDIP)

1

Note: See *Package Information* section for package drawing and dimensions.

1.4 Absolute Maximum Ratings

(T _A = +25°C, unless otherwise noted.)	
V ₊ to V ₋	44V
V ₊ to GND	25V
Digital Input Overvoltage Range	(V ₋ - 2V) to (V ₊ + 2V) or 20mA (whichever comes first)
Current (any terminal except S or D)	30mA
Continuous Current (S or D)	20mA
(pulsed at 1ms, 10% duty cycle max)	70mA
Power Dissipation (T _j = +150°C)	
up to +70°C	800mW
derate above +70°C	10mW/°C
Operating Temperature Range	-55°C to +125°C
Storage Temperature Range	-65°C to +150°C
Lead Temperature (soldering, 10 sec)	+300°C

1.5 Thermal Resistance $\Theta_{JC} = 50^{\circ}\text{C/W}$
 $\Theta_{JA} = 100^{\circ}\text{C/W}$



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2.0 REQUIREMENTS

2.1 Electrical performance characteristics are specified in Table 1 and apply over the full ambient operating temperature range, unless otherwise specified.

TABLE 1. ELECTRICAL PERFORMANCE CHARACTERISTICS (Note 1)

CHARACTERISTICS	SYMBOL	CONDITIONS		DEVICE TYPES	GROUP A SUB-GROUPS	LIMITS		UNITS
						MIN	MAX	
Analog-Signal Range	V _{ANALOG}	V _S = ±15V		All	1, 2, 3	-15	15	V
Drain-Source On Resistance	r _{DS(ON)}	I _S = 1mA, V _D = ±10V, V _{IN} = 11V (DG308A), V _{IN} = 3.5V (DG309)		All	1, 3	100		Ω
					2	150		
Source-Off Leakage Current	I _{S(OFF)}	V _{IN} = 3.5V (DG308A), V _{IN} = 11V (DG309)	V _S = 14V, V _D = -14V	All	1	-1	1	nA
			V _S = -14V, V _D = 14V		2	-100	100	
					1	-1	1	
					2	-100	100	
Drain-Off Leakage Current	I _{D(OFF)}	V _{IN} = 3.5V (DG308A), V _{IN} = 11V (DG309)	V _S = 14V, V _D = -14V	All	1	-1	1	nA
			V _S = -14V, V _D = 14V		2	-100	100	
					1	-1	1	
					2	-100	100	
Drain-On Leakage Current	I _{D(ON)}	V _{IN} = 11V (DG308A), V _{IN} = 3.5V (DG309)	V _S = V _D = 14V	All	1	-1	1	nA
			V _S = V _D = -14V		2	-100	100	
					1	-1	1	
					2	-100	100	
Input Current with Voltage High	I _{INH}	V _{IN} = 15V		All	1, 2	1		μA
Input Current with Voltage Low	I _{INL}	V _{IN} = 0V		All	1, 2	-1		μA
Positive Supply Current	I ₊	All channels on or off, V _{IN} = 0V or 15V		All	1, 3	10		μA
					2	100		
Negative Supply Current	I ₋	All channels on or off, V _{IN} = 0V or 15V		All	1, 3	-10		μA
					2	-100		
DYNAMIC								
Turn-On Time	t _{ON}	Figure 1		All	9	200		ns
					10, 11	400		
Turn-Off Time	t _{OFF}	Figure 1		All	9	150		ns
					10, 11	350		

Note 1: $V_+ = 15V$, $V_- = -15V$, $GND = 0V$, $V_{INH} = 11V$, $V_{INL} = 3.5V$, unless otherwise noted.

Quad, SPST, CMOS, TTL-Compatible Analog Switches

DG308A/DG309/883B

1

3.0 QUALITY ASSURANCE

- 3.1** Sampling and inspection procedures shall be in accordance with MIL-M-38510 and, to the extent specified, with MIL-STD-883.
- 3.2** Screening shall be in accordance with Method 5004 of MIL-STD-883. Burn-in test (Method 1015):
- (1) Test condition A, B, C, or D.
 - (2) $T_A = +125^{\circ}\text{C}$, minimum.
 - (3) Interim and final electrical test requirements shall be as specified in Table 2.
- 3.3** Quality conformance inspection shall be in accordance with Method 5005 of MIL-STD-883 including Groups A, B, C, and D inspection.
- Group A inspection:
- (1) Tests as specified in Table 2.
 - (2) Selected subgroups in Table 1, Method 5005 of MIL-STD-883 shall be omitted.
- 3.4** Groups C and D inspections:
- a. End-point electrical parameters shall be specified in Table 1.
 - b. Steady-state life test (Method 1005 of MIL-STD-883):
- (1) Test condition A, B, C, or D.
 - (2) $T_A = +125^{\circ}\text{C}$, minimum.
 - (3) Test duration, 1000 hours, except as permitted by Method 1005 of MIL-STD-883.

TABLE 2. ELECTRICAL TEST REQUIREMENTS

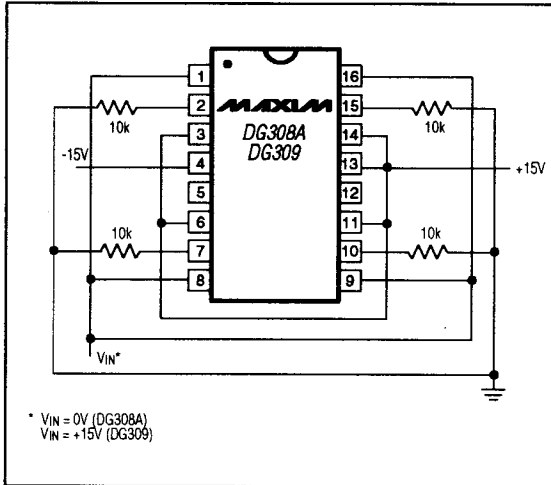
MIL-STD-883 Test Requirements	Subgroups (per Method 5005, Table 1)
Interim Electrical Parameters (Method 5004)	1
Final Electrical Parameters (Method 5004)	1,* 2, 3, 9
Group A Test Requirements (Method 5005)	1, 2, 3, 9, 10,** 11**
Groups C and D End-Point Electrical Parameters (Method 5005)	1

* PDA applies to Subgroup 1 only.

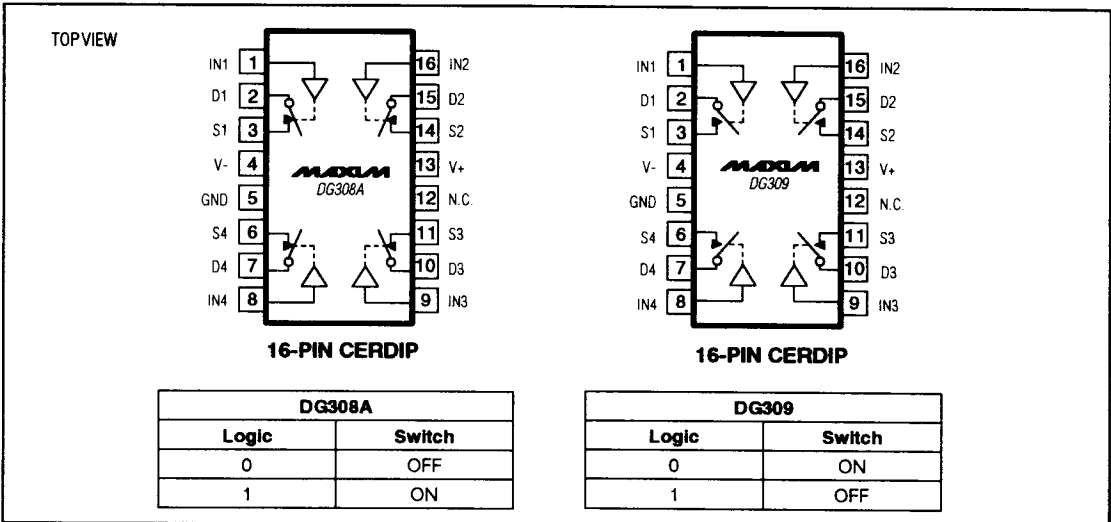
** Subgroups 10 and 11, if not tested, shall be guaranteed to the limits in Table 1.

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4.0 Life Test/Burn-In Circuit



4.1 Pin Configurations/Functional Diagrams



DG308A/DG309/883B

1

Figure 1. Switching-Time Test Circuit